## GaN on SiC HEMT Pulsed Power Transistor Production V1 250W Peak, 1200-1400 MHz, 300 s Pulse, 10\% Duty 18 Aug 11

## Features

- GaN depletion mode HEMT microwave transistor
- Internally matched
- Common source configuration
- Broadband Class AB operation
- RoHS Compliant
- +50V Typical Operation
- MTTF of 114 years (Channel Temperature $<200^{\circ} \mathrm{C}$ )


## Applications

- L-Band pulsed radar


## Product Description



The MAGX-001214-250L00 is a gold metalized matched Gallium Nitride (GaN) on Silicon Carbide RF power transistor optimized for pulsed L-Band radar applications. Using state of the art wafer fabrication processes, these high performance transistors provide high gain, efficiency, bandwidth, ruggedness over a wide bandwidth for today's demanding application needs. High breakdown voltages allow for reliable and stable operation in extreme mismatched load conditions unparalleled with older semiconductor technologies.

## Typical RF Performance at Pout = 250W Peak

| Freq <br> $(\mathbf{M H z})$ | Pin <br> $(\mathbf{W})$ | Gain <br> $(\mathbf{d B})$ | Slope <br> $(\mathbf{d B})$ | Id <br> $(\mathbf{A})$ | Eff <br> $(\%)$ | Avg-Eff <br> $(\%)$ | RL <br> $(\mathbf{d B})$ | Droop <br> $(\mathbf{d B})$ |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 1200 | 4.4 | 17.6 | - | 8.0 | 62.2 | - | -13.3 | 0.4 |
| 1250 | 4.0 | 18.0 | - | 8.2 | 60.4 | - | -19.2 | 0.5 |
| 1300 | 4.1 | 17.8 | - | 8.7 | 57.1 | - | -22.6 | 0.6 |
| 1350 | 4.4 | 17.5 | - | 9.1 | 54.6 | - | -19.2 | 0.7 |
| 1400 | 4.4 | 17.6 | 0.5 | 9.0 | 55.0 | 57.9 | -19.8 | 0.6 |

## Ordering Information

MAGX-001214-250L00 250W GaN Power Transistor MAGX-001214-SB1PPR Evaluation Fixture

|  |  |
| :---: | :---: |
| Supply Voltage ( $\mathrm{V}_{\mathrm{DD}}$ ) | +65V |
| Supply Voltage (VGS) | -8 to -2V |
| Supply Current ( $\mathrm{Idmax}^{\text {) }}$ | 8.8 Apk |
| Input Power (PiN) | +40 dBm |
| Absolute Max. Junction/Channel Temp | $200{ }^{\circ} \mathrm{C}$ |
| MTTF ( $\mathrm{T}^{\prime}<200^{\circ} \mathrm{C}$ ) | 114 years |
| Pulsed Power Dissipation at $85^{\circ} \mathrm{C}$ | 192 Wpk |
| Thermal Resistance, $\left(\mathrm{Tj}=70^{\circ} \mathrm{C}\right)$ $V_{D D}=50 \mathrm{~V}, \mathrm{I}_{\mathrm{DQ}}=250 \mathrm{~mA}$, Pout $=250 \mathrm{~W}$ 300us Pulse / 10\% Duty | $0.60^{\circ} \mathrm{C} / \mathrm{W}$ |
| Operating Temp | -40 to $+95^{\circ} \mathrm{C}$ |
| Storage Temp | -65 to $+150^{\circ} \mathrm{C}$ |
| Mounting Temperature | See solder reflow profile |
| ESD Min. - Machine Model (MM) | 50 V |
| ESD Min. - Human Body Model (HBM) | >250V |
| MSL Level | MSL1 |

(1) Operation of this device above any one of these parameters may cause permanent damage.
(2) Channel temperature directly affects a device's MTTF. Channel temperature should be kept as low as possible to maximize lifetime
(3) For saturated performance it recommended that the sum of $\left(3^{*} \mathrm{Vdd}+\mathrm{abs}(\mathrm{Vgg})\right)<175$

| Parameter | Test Conditions | Symbol | Min | Typ | Max | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| DC CHARACTERISTICS |  |  |  |  |  |  |
| Drain-Source Leakage Current | $V_{G S}=-8 \mathrm{~V}, \mathrm{~V}_{\mathrm{DS}}=175 \mathrm{~V}$ | $\mathrm{l}_{\text {DS }}$ | - | 0.4 | 12 | mA |
| Gate Threshold Voltage | $\mathrm{V}_{\mathrm{DS}}=5 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=30 \mathrm{~mA}$ | $\mathrm{V}_{\mathrm{GS}}(\mathrm{th})$ | -5 | -3.1 | -2 | V |
| Forward Transconductance | $\mathrm{V}_{\mathrm{DS}}=5 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=7.0 \mathrm{~mA}$ | $\mathrm{G}_{\mathrm{M}}$ | 5.0 | 7.7 | - | S |
| DYNAMIC CHARACTERISTICS |  |  |  |  |  |  |
| Input Capacitance | Not applicable-Input internally matched | $\mathrm{C}_{\text {ISS }}$ | N/A | N/A | N/A | pF |
| Output Capacitance | $\mathrm{V}_{\mathrm{DS}}=50 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=-8 \mathrm{~V}, \mathrm{~F}=1 \mathrm{MHz}$ | Coss | - | 22 | - | pF |
| Feedback Capacitance | $\mathrm{V}_{\mathrm{DS}}=50 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=-8 \mathrm{~V}, \mathrm{~F}=1 \mathrm{MHz}$ | $\mathrm{C}_{\text {RSS }}$ | - | 2.2 | - | pF |

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Electrical Specifications: $\mathrm{T}_{\mathrm{C}}=\mathbf{2 5} \pm 5^{\circ} \mathrm{C}$ (Room Ambient)

| Parameter | Test Conditions | Symbol | Min | Typ | Max | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| RF FUNCTIONAL TESTS ( $\mathrm{V}_{\mathrm{DD}}=50 \mathrm{~V}, \mathrm{I}_{\mathrm{DQ}}=250 \mathrm{~mA}, 300 \mathrm{us} / 10 \%$ duty, $\mathbf{1 2 0 0 - 1 4 0 0 \mathrm { MHz }}$ ) |  |  |  |  |  |  |
| Input Power | Pout = 250W Peak (25W avg) | PIN | - | 4.2 | 5.6 | Wpk |
| Power Gain | Pout = 250W Peak (25W avg) | $\mathrm{G}_{\mathrm{P}}$ | 16.5 | 17.7 | - | dB |
| Drain Efficiency | Pout = 250W Peak (25W avg) | $\eta_{\mathrm{D}}$ | 50 | 57.9 | - | \% |
| Load Mismatch Stability | Pout = 250W Peak (25W avg) | VSWR-S | 5:1 | - | - | - |
| Load Mismatch Tolerance | Pout = 250W Peak (25W avg) | VSWR-T | 10:1 | - | - | - |

## Test Fixture Impedance

| $\mathbf{F}(\mathbf{M H z})$ | $\mathbf{Z}_{\mathbf{I F}} \mathbf{( \Omega )}$ | $\mathbf{Z}_{\mathbf{O F}}(\mathbf{\Omega})$ |
| :---: | :---: | :---: |
| 1200 | $3.6-\mathrm{j} 5.3$ | $3.5+\mathrm{j} 0.7$ |
| 1250 | $3.3-\mathrm{j} 4.9$ | $3.7+\mathrm{j} 0.2$ |
| 1300 | $3.2-\mathrm{j} 4.4$ | $3.5-\mathrm{j} 0.3$ |
| 1350 | $3.2-\mathrm{j} 4.0$ | $3.2-\mathrm{j} 0.6$ |
| 1400 | $3.2-\mathrm{j} 3.6$ | $2.7-\mathrm{j} 0.7$ |



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RF Power Transfer Curve (Output Power Vs. Input Power)


RF Power Transfer Curve (Drain Efficiency Vs. Output Power)


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PRELIMINARY: Data Sheets contain information regarding a product M/A-COM Technology Solutions has under development. Performance is based on engineering tests. Specifications are typical. Mechanical outline has been fixed. Engineering samples nd/f tes at tar ay br ave il-

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Test Fixture Circuit Dimensions


Test Fixture Assembly


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## Outline Drawing



## CORRECT DEVICE SEQUENCING

## TURNING THE DEVICE ON

1. Set $\mathrm{V}_{\mathrm{GS}}$ to the pinch-off $\left(\mathrm{V}_{\mathrm{P}}\right)$, typically -5 V
2. Turn on $\mathrm{V}_{\mathrm{DS}}$ to nominal voltage ( 50 V )
3. Increase $\mathrm{V}_{G S}$ until the $\mathrm{I}_{\mathrm{DS}}$ current is reached
4. Apply RF power to desired level

## TURNING THE DEVICE OFF

1. Turn the RF power off
2. Decrease $V_{G S}$ down to $V_{P}$
3. Decrease $V_{D S}$ down to $0 V$
4. Turn off $\mathrm{V}_{\mathrm{GS}}$
